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FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))	Attorney Docket No.: L&L-I0217 Appl. No.: 10/620,093 Applicant: JÖRG BERTHOLD ET AL. Filing Date: July 15, 2003 Group Art Unit: 2825

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES	TRANSL. NO
	J	199 00 974 A1	9/16/99	Germany	G01R	31/3183	Abstract	
	K	0 259 705 B1	3/16/88	Europe	606F	15/60	✓	
	L	93/18468	9/16/93	WIPO	G06F	15/60	✓	
	M							
	N							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

		International Preliminary Examination Report for PCT/DE01/04457, pp 1-7, English translation, filed 11/24/2003.
		Bowman, K. A. et al.: "Impact of Extrinsic and Intrinsic Parameter Fluctuations on CMOS Circuit Performance", IEEE Journal of Solid-State Circuits, Vol. 35, No. 8, August 2000, pp. 1186-1193
		Eisele, M. et al.: "The Impact of Intra-Die Device Parameter Variations on Path Delays and on the Design for Yield of Low Voltage Digital Circuits", IEEE Transactions on Very Large Scale Integration (VLSI) Systems, Vol. 5, No. 4, December 1997, pp. 360-368

EXAMINER	DATE CONSIDERED
Phallaka Kik	10/19/2005